XY Piezo Positioning Flexure Stages

Nanometer and Picometer Resolution, High Speed & Stability

FAST

PRECISE

INDIVIDUAL

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XY Piezo Nanopositioning Scanners & Stages

P-713 XY Piezo Scanner with aperture for imaging etc

P-915KXYS Low-cost open-loop XY imaging scanner

P-612.2SL economical XY piezo nanopositioning stage with aperture

P-734 high-performance low-bow flexure nanopositioning stage with ultra-precise trajectory control

PIHera® XY piezo nanopositioning systems provide travel ranges from 50x50µm to 1800x1800 µm

P-611 low cost XY- and XZ-nanopositioning systems, 100 µm travel, closed-loop option

P-733.2DD, high-speed, direct drive nanopositioning scanning stage. Fastest multi-axis piezo stage with large aperture and capacitive feedback (2.2 kHz resonant frequency!)

P-517 /P-527 nanopositioning stage family provides many options and travel ranges. Up to 6 axes

The P-541/P-542- nanopositioning stage family. Very low profile (16.5mm), large 80x80mm aperture, highly accurate motion: sub-nanometer resolution

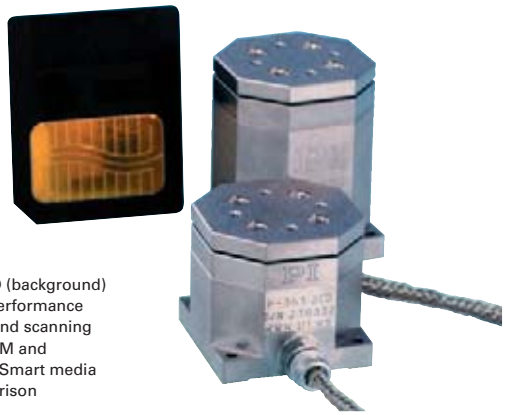
P-363 PicoCube™ XY and XYZ Scanners for AFM. Closed loop, capacitive feedback. 5µm travel, 30 Picometer resolution

PInano™ XY and XYZ microscope scanner stage for Super Resolution-microscopy applications

P-313 PicoCube® XY and XYZ Scanners for AFM. Lead-free piezo material provides ultra-high linearity. No servo lag!

P-363 PicoCube™ XY(Z) Piezo Scanner

High-Dynamics Nanoscanner for Scanning Probe Microscopy



P-363.2CD and .3CD (background) PicoCube™, high-performance piezo positioning- and scanning systems or AFM/STM and nanomanipulation. Smart media card for size comparison

- **Ultra-High-Performance Closed-Loop Scanner for AFM/SPM**
- **Compact Manipulation Tool for Bio/Nanotechnology**
- **Resonant Frequency 9.8 kHz**
- **Capacitive Sensors for Highest Accuracy**
- **Parallel-Motion Metrology for Automated Compensation of Guiding Errors**
- **50 Picometer Resolution**
- **5 x 5 x 5 µm Travel Range**
- **Vacuum-Compatible Versions**

The P-363 PicoCube™ XY/XYZ is an ultra-high-performance closed-loop piezo scanning system. Designed for AFM, SPM and nanomanipulation applications, it combines an ultra-low inertia, high-speed XY/XYZ piezo scanner with non-contact, direct-measuring, parallel-metrology capacitive feedback capable of 50 picometers resolution. On top of being extremely precise, the PicoCube™ system is also very small and rugged. Measuring only 30 x 30 x 40 mm (with removable top plate, 30 x 30 x 28 mm for XY version), it is easy to integrate in any scanning apparatus.

Application Examples

- Scanning microscopy (SPM)
- Biotechnology
- Micromanipulation
- Nanopositioning
- Nano-imprinting
- Nanometrology
- Nanolithography

SPM, AFM, STM, Nanolithography, Nanoimprinting, Nanometrology

The PicoCube™ was specifically developed to overcome the limitations of the open-loop scanners currently available for SPM, AFM and STM. In addition to these applications, the PicoCube™ is also the ideal scanning and manipulation tool for nanoimprinting, nanolithography, ultra-high-resolution, near-field, scanning optical microscopy and nanosurface-metrology applications.

Higher Precision Through Parallel-Motion Metrology w/ Capacitive Sensors

The PicoCube™ is based on a proprietary, ultra-fast, piezo-driven scanner design equipped with direct-measuring, capacitive position sensors (parallel metrology). Unlike conventional sensors, they measure the actual distance between the fixed frame and the moving part of the stage. This results in higher-motion linearity, long-term stability, phase fidelity, and—because external disturbances are seen by the sensor immediately—a stiffer, faster-responding servo-loop.

Multi-axis nanopositioning systems equipped with parallel direct metrology are able to measure the platform position in all degrees of freedom against one fixed reference. In such systems, undesirable motion from one actuator in the direction of another (cross-talk) is detected immediately and act ively compensated by the servo-loops. This Active Trajectory Control Concept can keep deviation from a trajectory to under a few nanometers, even in dynamic operation.

Ordering Information

P-363.3CD
PicoCube™ High-Precision XYZ Nanopositioning System, 5 x 5 x 5 µm, Parallel Metrology, Capacitive Sensors, Sub-D Connector

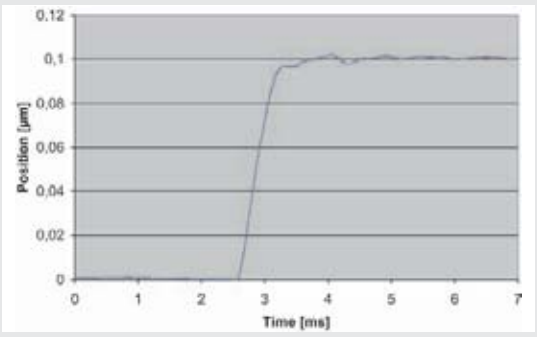
P-363.3UD
PicoCube™ High-Precision XYZ Nanopositioning System, 5 x 5 x 5 µm, Parallel Metrology, Capacitive Sensors, Sub-D Connector, Vacuum Compatible to 10^{-9} hPa

P-363.2CD
PicoCube™ High-Precision XY Nanopositioning System, 5 x 5 µm, Parallel Metrology, Capacitive Sensors, Sub-D Connector

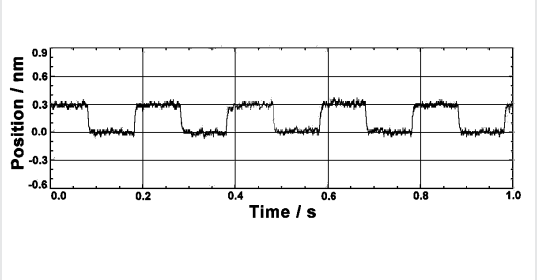
P-363.2UD
PicoCube™ High-Precision XY Nanopositioning System, 5 x 5 µm, Parallel Metrology, Capacitive Sensors, Sub-D Connector, Vacuum Compatible to 10^{-9} hPa

P-363.3CL
PicoCube™ High-Precision XYZ Nanopositioning System, 5 x 5 x 5 µm, Parallel Metrology, Capacitive Sensors, LEMO Connector

P-363.2CL
PicoCube™ High-Precision XY Nanopositioning System, 5 x 5 µm, Parallel Metrology, Capacitive Sensors, LEMO Connector



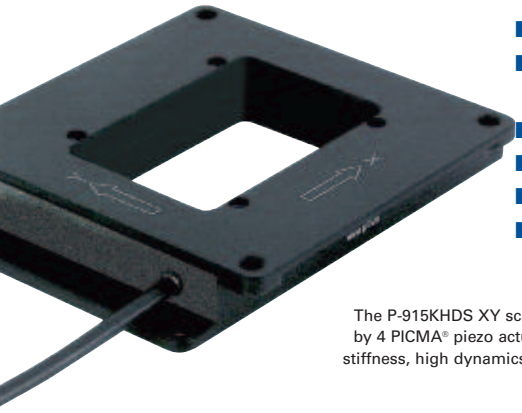
The P-363 settles to within 1 nm in 1 ms (100 nm step, X and Y motion; faster response in Z)



300 picometer steps (0.3 nm) performed with the P-363, measured with an external high-resolution, capacitive measurement system

P-915K High-Dynamics XY Piezo Scanner

Cost-Effective OEM Slide with Large Aperture for Imaging Applications



- **Direct Drive for High Dynamics**
- **Scanning Stage for Pixel Sub-Stepping: Enhances Image Resolution**
- **Cost-Efficient Design**
- **15 x 15 µm Travel Range**
- **Load Capacity to 5 N**
- **Clear Aperture 30 x 45 mm**

Model	Travel range	Resolution	Resonant frequency
P-915KHDS High-Dynamics XY Scanner	15 x 15 µm	0.1 nm	1850 Hz

Dimensions

Baseplate
85 x 54 mm
Moved platform
69 x 69 mm
Clear aperture
30 x 45 mm

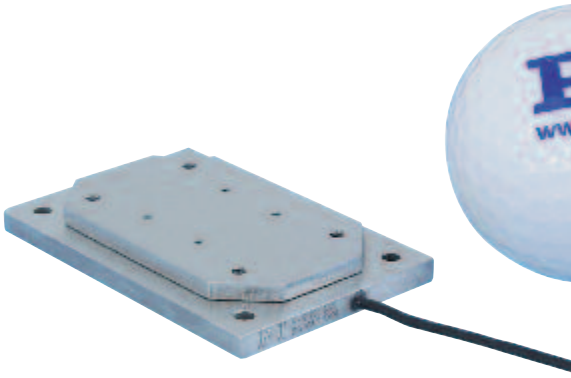
The P-915KHDS XY scanning stage is driven by 4 PICMA® piezo actuators to provide high stiffness, high dynamics and superior lifetime

P-915K Fast XY Piezo Scanner

Cost-Effective OEM Slide for Imaging

- **For Pixel Sub-Stepping to Enhance Image Resolution**
- **Compact Design: 40 x 60 x 7 mm**
- **Highly Cost-Efficient Open-Loop Design**
- **Travel Ranges to 4 x 4 µm**
- **Parallel Kinematics for Enhanced Dynamics and Better Multi-Axis Accuracy**

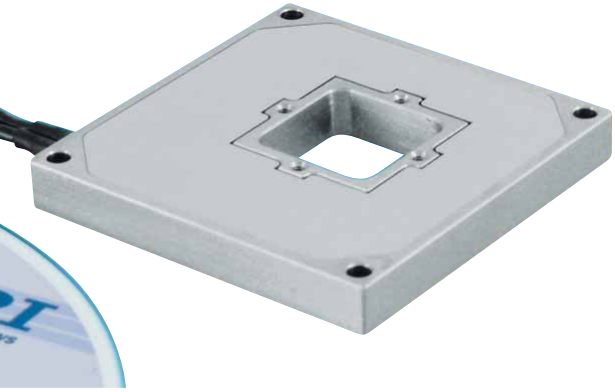
Model	Travel	Resolution	Load capacity	Dimensions
P-915KXYS XY Scanner	4 x 4 µm	0.4 nm	50 g	40 x 60 x 7 mm



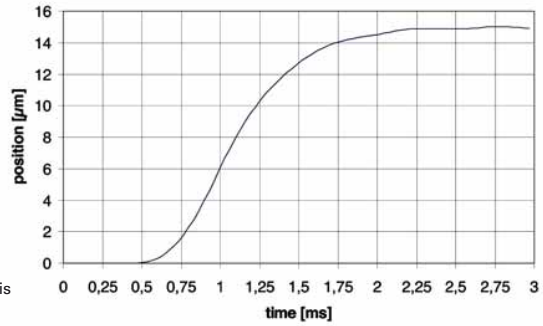
The fast P-915KXYS open-loop XY scanner is ideally suited for image enhancement e.g. for CCD chips

P-713 XY Piezo Flexure Scanner

OEM System with Aperture and low Profile



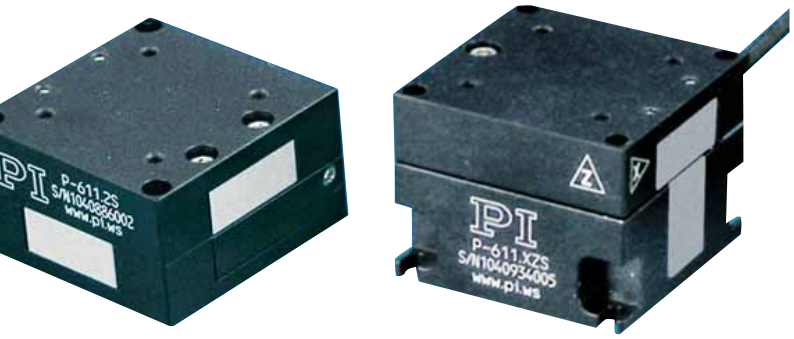
- **Ideal for Pixel Sub-Stepping in Image Enhancement**
- **Small Footprint and Low Profile: 45 x 45 x 6 mm with Clear Aperture**
- **Very Cost-Effective Design**
- **Travel Ranges to 20 x 20 µm**
- **Parallel Kinematics for Better Multi-Axis Accuracy and Dynamics**



Settling time for the P-713 at 15 µm is in the 2 ms range

P-611.XZ · P-611.2 XZ & XY Nanopositioner

Compact 2-Axis Piezo System for Nanopositioning Tasks



P-611 XY- and XZ-nanopositioning systems (from left), 100 µm travel, resolution to 0.2 nm

- **Compact: Footprint 44 x 44 mm**
- **Travel Range to 120 x 120 µm**
- **Resolution to 0.2 nm**
- **Cost-Effective Mechanics/Electronics System Configurations**
- **Frictionless, High-Precision Flexure Guiding System**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**
- **X, Z and XYZ Versions also Available**

P-611 piezo stages are flexure-guided nanopositioning systems featuring a compact footprint of only 44 x 44 mm. The XY- and XZ-versions described here are part of a family of positioners available in 1 to 3 axis configurations. Despite their small dimensions the systems provide up to 120 µm travel with sub-nanometer resolution. They are ideally suited for planar positioning tasks such as opticalpath length correction in interferometry, sample positioning in microscopy or scanning applications, for autofocus and photonics applications. Both versions are available with 100 µm travel per axis. Equipped with ceramic-encapsulated piezo drives and a stiff, zero-stiction, zero-friction flexure guiding system, all P-611 piezo stages combine millisecond responsiveness with nanometric precision and extreme reliability.

Application Examples

- Fiber positioning
- Semiconductor testing
- Micromachining
- Micromanipulation
- MEMS fabrication/testing
- Photonics / integrated optics

Closed-Loop and Open-Loop Versions

High-resolution, fast-responding, strain gauge sensors (SGS) are applied to appropriate locations on the drive train and provide a high-bandwidth, nanometer-precision position feedback signal to the controller. The sensors are connected in a full-bridge configuration to eliminate thermal drift, and assure optimal position stability in the nanometer range.

The open-loop models are ideal for applications where fast response and very high resolution are essential, but absolute positioning is not important. They can also be used when the position is controlled by an external linear position sensor such as an interferometer, a PSD (position sensitive diode), CCD chip / image processing system, or the eyes and hands of an operator.

Versatility & Combination with Motorized Stages

The P-611 family of piezo stages comprises a variety of single- and multi-axis versions (X, XY, Z, XZ and XYZ) that can be easily combined with a number of very compact manual or motorized micropositioning systems to form coarse/fine positioners with longer travel ranges (see p. 2-20, p. 2-36 and p. 2-50).

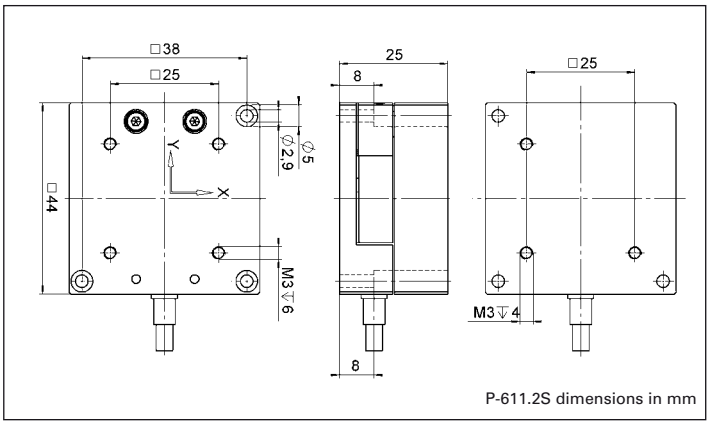
Ordering Information

P-611.2S
XY Nanopositioning System, 100 x 100 µm, SGS-Sensor

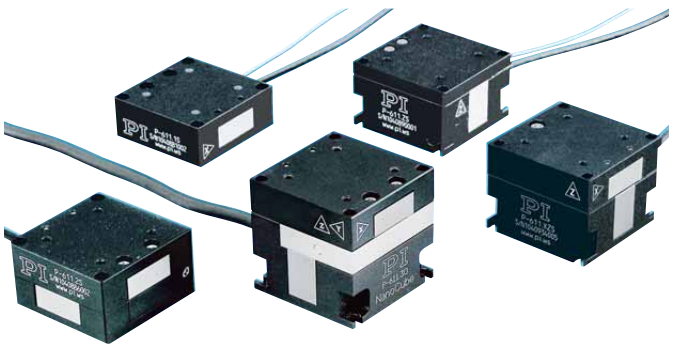
P-611.20
XY Nanopositioning System, 100 x 100 µm, No Sensor

P-611.XZS
XZ Nanopositioning System, 100 x 100 µm, SGS-Sensor

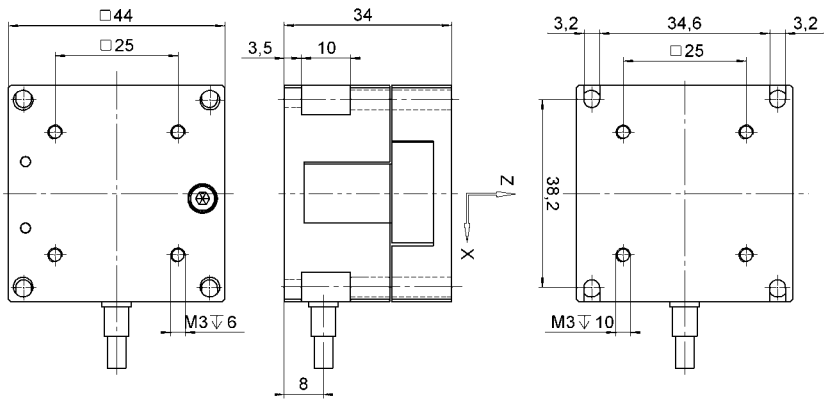
P-611.XZ0
XZ Nanopositioning System, 100 x 100 µm, No Sensor



P-611.2S dimensions in mm



The whole P-611 family: X, Z, XY, XZ and XYZ stages



P-611.XZS dimensions in mm

Technical Data

Model	P-611.2S	P-611.20	P-611.XZS	P-611.XZ0	Units	Tolerance
Active axes	X, Y	X, Y	X, Z	X, Z		
Motion and positioning						
Integrated sensor	SGS	–	SGS	–		
Open-loop travel, -20 to +120 V	120	120	120	120	µm	min. (+20 %/0 %)
Closed-loop travel	100	–	100	–	µm	
Open-loop resolution	0.2	0.2	0.2	0.2	nm	typ.
Closed-loop resolution	2	–	2	–	nm	typ.
Linearity	0.1	–	0.1	–	%	typ.
Repeatability	<10	–	<10	–	nm	typ.
Pitch in X,Y	±5	±5	±5	±5	µrad	typ.
Runout θ_X (Z motion)	–	–	±10	±10	µrad	typ.
Yaw in X	±20	±20	±20	±20	µrad	typ.
Yaw in Y	±10	±10	–	–	µrad	typ.
Runout θ_Y (Z motion)	–	–	±10	+/-10	µrad	typ.
Mechanical properties						
Stiffness	0.2	0.2	0.2 Z: 0.35	0.2 Z: 0.35	N/µm	±20 %
Unloaded resonant frequency	X: 345; Y: 270	X: 345; Y: 270	X: 365; Z: 340	X: 365; Z: 340	Hz	±20 %
Resonant frequency @ 30 g	X: 270; Y: 225	X: 270; Y: 225	X: 280; Z: 295	X: 280; Z: 295	Hz	±20 %
Resonant frequency @ 100 g	X: 180; Y: 165	X: 180; Y: 165	X: 185; Z: 230	X: 185; Z: 230	Hz	±20 %
Push/pull force capacity in motion direction	15 / 10	15 / 10	15 / 10	15 / 10	N	Max.
Load capacity	15	15	15	15	N	Max.
Drive properties						
Ceramic type	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885		
Electrical capacitance	1.5	1.5	1.5	1.5	µF	±20 %
Dynamic operating current coefficient	1.9	1.9	1.9	1.9	µA/(Hz • µm)	±20 %
Miscellaneous						
Operating temperature range	-20 to 80	-20 to 80	-20 to 80	-20 to 80	°C	
Material	Aluminum, steel	Aluminum, steel	Aluminum, steel	Aluminum, steel		
Dimensions	44 x 44 x 25	44 x 44 x 25	44 x 44 x 34	44 x 44 x 34	mm	
Mass	0.235	0.235	0.27	0.27	kg	±5 %
Cable length	1.5	1.5	1.5	1.5	m	±10 mm
Sensor connection	LEMO	–	LEMO	–		
Voltage connection	LEMO	LEMO	LEMO	LEMO		

Resolution of PI Piezo Nanopositioners is not limited by friction or stiction. Value given is noise equivalent motion with E-503 amplifier (p. 2-146)
Dynamic Operating Current Coefficient in µA per Hz and µm. Example: Sinusoidal scan of 50 µm at 10 Hz requires approximately 0.9 mA drive current.
Recommended controller / amplifier
Single-channel (1 per axis): E-610 servo controller / amplifier (p. 2-110), E -625 servo controller, bench-top (p. 2-114), E-621 controller module (p. 2-160)
Multi-channel: modular piezo controller system E-500 (p. 2-142) with amplifier module E-503 (three channels) (p. 2-146) or E-505 (1 per axis, high-power) (p. 2-147) and E-509 controller (p. 2-152)

P-620.2 - P-629.2 PIHera® XY Piezo Stage

High-Precision Nanopositioner Family–Compact and Long Travel Ranges

PIHera® XY nanopositioning systems provide travel ranges from 50 x 50 µm to 1800 x 1800 µm

- **Travel Ranges 50 to 1800 µm**
- **High-Precision, Cost-Efficient**
- **Resolution to 0.1 nm**
- **Frictionless, High-Precision Flexure Guiding System**
- **0,02 % Positioning Accuracy**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**
- **X-, XY-, Z- and XYZ-Versions**
- **Vacuum-Compatible Versions Available**

Two-axis (XY) PIHera® systems are piezo-nanopositioning stages featuring travel ranges from 50 to 1800 µm. Despite the increased travel ranges, the units are extremely compact and provide rapid response and high guiding precision. This, and the long travel range is achieved with a friction-free and extremely stiff flexure system sub-nanometer resolution. The PIHera® piezo nanopositioning series also includes Z and X stages (see p. 2-22 and p. 2-40).

Application Examples

- Interferometry
- Microscopy
- Nanopositioning
- Biotechnology
- Quality assurance testing
- Semiconductor technology

Nanometer Precision in Milliseconds

One of the advantages of PIHera® stages over motor-driven positioning stages is the rapid response to input changes and the fast and precise settling behavior. The P-622.1CD, for example, can settle to an accuracy of 10 nm in only 30 msec (other PI stages provide even faster response)!

Superior Accuracy With Direct-Metrology Capacitive Sensors

A choice of tasks such as optical path adjustment in interferometry, sample positioning in microscopy, precision alignment or optical tracking require the relatively long scanning ranges and nanometer precision offered by PIHera® nanopositioning stages.

PI's proprietary capacitive sensors measure position directly and without physical contact. They are free of friction and hysteresis, a fact which, in combination with the positioning resolution of well under 1 nm, makes it possible to achieve very high levels of linearity. A further advantage of direct metrology with capacitive sensors is the high phase fidelity and the high bandwidth of up to 10 kHz.

Designed for Precision

High stiffness is achieved with the FEA-optimized design of the frictionless flexure elements, which assure excellent guiding accuracy and dynamics. A straightness and flatness in the nanometer range is achieved.

Ordering Information

P-620.2CD* / P-620.2CL*
PIHera® Precision XY Nanopositioning System,
50 x 50 µm, Direct Metrology, Capacitive Sensors

P-621.2CD* / P-621.2CL*
PIHera® Precision XY Nanopositioning System,
100 x 100 µm, Direct Metrology, Capacitive Sensors

P-622.2CD* / P-622.2CL*
PIHera® Precision XY Nanopositioning System,
250 x 250 µm, Direct Metrology, Capacitive Sensors

P-625.2CD* / P-625.2CL*
PIHera® Precision XY Nanopositioning System,
500 x 500 µm, Direct Metrology, Capacitive Sensors

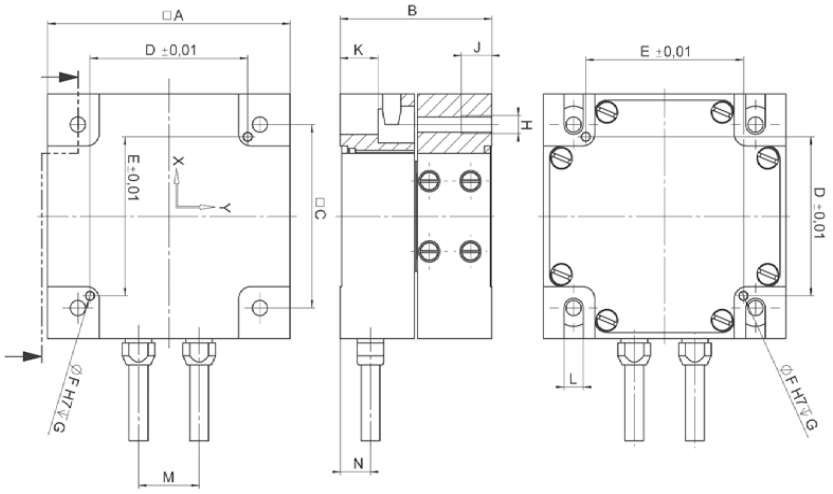
P-628.2CD* / P-628.2CL*
PIHera® Precision XY Nanopositioning System,
800 x 800 µm, Direct Metrology, Capacitive Sensors

P-629.2CD* / P-629.2CL*
PIHera® Precision XY Nanopositioning System,
1500 x 1500 µm, Direct Metrology, Capacitive Sensors

*.2CD with Sub-D Connector
*.2CL with LEMO Connector

Open-loop versions are available as P-62x.20L.
Vacuum versions to 10^{-9} hPa are available as P-62x.2UD.

Single-axis PIHera® nanopositioning system with travel range to 1800 µm



	A	B	C	D	E	⌀F	G	H	J	K	L	M	N
P-620.2CD /20L	30	21,5	24	24	19	1,01	1,5	M2	3,5	5,1	2,2	9	6
P-621.2CD / 20L	40	25	30	26	26	1,51	2,5	M3	5	6,25	3,2	10	5
P-622.2CD / 20L	50	25	40	35	35	1,51	2,5	M3	5	6,25	3,2	11	5
P-625.2CD / 20L	60	25	50	46	46	1,51	2,5	M3	6	6,25	3,2	11	5
P-628.2CD / 20L	80	30	70	66	66	1,51	2,5	M3	6	6,75	3,2	11	5
P-629.2CD / 20L	100	40	90	82	82	2,01	3,5	M4	7	9,75	4,3	16	7,5

P-62x.2CD/.2CL/.20L dimensions in mm

Technical Data

Model	P-620.2CD/ P-620.2CL	P-621.2CD/ P-621.2CL	P-622.2CD/ P-622.2CL	P-625.2CD/ P-625.2CL	P-628.2CD/ P-628.2CL	P-629.2CD P-629.2CL	P-62x.20L open-loop versions	Units	Tolerance
Active axes	X, Y	X, Y	X, Y	X, Y	X, Y	X, Y	X, Y		
Motion and positioning									
Integrated sensor	Capacitive	Capacitive	Capacitive	Capacitive	Capacitive	Capacitive	–		
Open-loop travel X, Y, -20 to +120 V	60	120	300	600	950	1800	as P-62x.2CD	µm	min. (+20 %/-0 %)
Closed-loop travel	50	100	250	500	800	1500	–	µm	
Open-loop resolution	0.1	0.2	0.4	0.5	0.5	2	as P-62x.2CD	nm	typ.
Closed-loop resolution	0.2	0.4	0.7	1.4	3.5	3.5	–	nm	typ.
Linearity	0.02	0.02	0.02	0.03	0.03	0.03	–	%	typ.
Repeatability	±2	±2	±2	±5	±10	±14	as P-62x.2CD	nm	typ.
Pitch / yaw	±3	±3	±3	±3	±20	±30	as P-62x.2CD	µrad	typ.
Mechanical properties									
Stiffness	0.22	0.25	0.2	0.1	0.05	0.1	as P-62x.2CD	N/µm	±20 %
Unloaded resonant frequency in X,	575	420	225	135	75	60	as P-62x.2CD	Hz	±20 %
Unloaded resonant frequency in Y	800	535	300	195	105	100	as P-62x.2CD	Hz	±20 %
Resonant frequency in X @ 50 g	270	285	180	120	60	55	as P-62x.2CD	Hz	±20 %
Resonant frequency in Y @ 50 g	395	365	215	150	85	85	as P-62x.2CD	Hz	±20 %
Resonant frequency in X @ 100 g	285	220	160	105	55	50	as P-62x.2CD	Hz	±20 %
Resonant frequency in Y @ 100 g	300	285	175	125	75	80	as P-62x.2CD	Hz	±20 %
Push/pull force capacity in motion direction	10 / 5	10 / 8	10 / 8	10 / 8	10 / 8	10 / 8	as P-62x.2CD	N	Max.
Load capacity	10	10	10	10	10	10	as P-62x.2CD	N	Max.
Lateral Force	10	10	10	10	10	10	as P-62x.2CD	N	Max.
Drive properties									
Ceramic type	PICMA® P-883	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-887	PICMA® P-888	as P-62x.2CD		
Electrical Capacitance	0.35	1.5	3.1	6.2	19	52	as P-62x.2CD	µF	±20 %
Dynamic operating current coefficient	0.9	1.9	1.9	1.6	3	4.3	as P-62x.2CD	µA/(Hz•µm)	±20 %
Miscellaneous									
Operating temperature range	-20 to 80	-20 to 80	-20 to 80	-20 to 80	-20 to 80	-20 to 80	-20 to 150	°C	
Material	Aluminum	Aluminum	Aluminum	Aluminum	Aluminum	Aluminum	Aluminum		
Mass	0.195	0.295	0.348	0.43	0.7	1.37	as P-62x.2CD	kg	±5 %
Cable length	1.5	1.5	1.5	1.5	1.5	1.5	1.5	m	±10 mm
Sensor / voltage connection	CD version: 2x Sub-D special CL version: LEMO	CD version: 2x Sub-D special CL version: LEMO	CD version: 2x Sub-D special CL version: LEMO	CD version: 2x Sub-D special CL version: LEMO	CD version: 2x Sub-D special CL version: LEMO	CD version: 2x Sub-D special CL version: LEMO	2x LEMO (no sensor)		

Lower axis: X; upper axis: Y.
Resolution of PI Piezo Nanopositioners is not limited by friction or stiction. The value given is noise equivalent motion with E-710 controller (p. 2-128)
Recommended controller
CD version: E-610 servo controller / amplifier (p. 2-110), E-625 servo controller, bench-top (p. 2-114), E-665 powerful servo controller, bench-top (p. 2-116)
Multi-channel digital controllers: E-710 bench-top (p. 2-128), E-712 modular (p. 2-140), E-725 high-power (p. 2-126), E-761 PCI board (p. 2-140)
CL version: E-500 modular piezo controller system (p. 2-142) with E-505 amplifier module (1 per axis, high power) (p. 2-147) and E-509 controller (p. 2-152)
Open-loop versions: E-500 modular piezo controller system (p. 2-142) with E-505 amplifier module (1 per axis, high power) (p. 2-147)

P-612 XY Piezo Nanopositioning System

Compact, Clear Aperture

P-612.2SL XY piezo stage (CD for size comparison)

- **Compact: Footprint 60 x 60 mm**
- **100 x 100 µm Closed-Loop Travel Range (130 x 130 Open-Loop)**
- **For Cost-Sensitive Applications**
- **Clear Aperture 20 x 20 mm**
- **Parallel-Kinematics for Enhanced Responsiveness / Multi-Axis Precision**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**
- **Z-Stage Also Available**

The P-612.2SL is a piezo-based nanopositioning system featuring a compact footprint of only 60 x 60 mm and a height of 18 mm. Due to the 20 x 20 mm open aperture, the system is excellently suited for sample positioning in microscopy or scanning applications. Equipped with piezo drives and zero-stiction, zero-friction flexure guiding system, the series provides nanometer-range resolution and millisecond response time. A Z stage with the same form factor is available for vertical positioning applications (see P-612.ZSL p. 2-38).

Cost-Effective Design

Flexures optimized with Finite Element Analysis (FEA) are used to guide the compact, low-cost stage. Flexures allow extremely high-precision motion, no matter how minute, as they are completely free of play and friction. They also optimize stiffness in and perpendicular to the direction of motion.

Position Servo-Control with Nanometer Resolution

High-resolution, broadband, strain gauge sensors (SGS) are applied to appropriate locations on the drive train and measure the displacement of the moving part of the stage relative to the base directly. The SGS sensors assure optimum position stability in the nanometer range and fast response.

The open-loop models are ideal for applications where fast response and very high resolution are essential, but absolute positioning is not important. They can also be used in applications where the position is controlled by an external linear position sensor such as an interferometer, a PSD (position sensitive diode), CCD chip / image processing system, or the eyes and hands of an operator.

Ordering Information

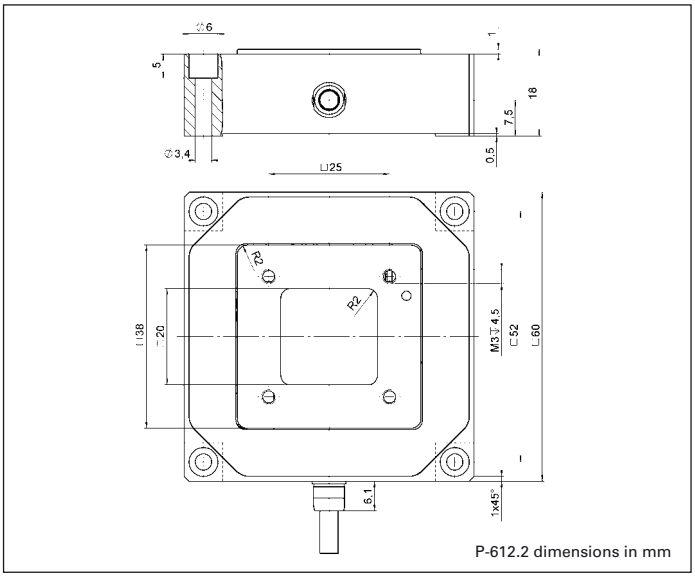
P-612.2SL
XY Nanopositioning System with 20 x 20 mm Aperture, 100 x 100 µm, Strain Gauge Sensors

P-612.20L
XY Nanopositioning System with Aperture 20 x 20 mm, 100 x 100 µm, Open-Loop

Ceramic Insulated Piezo Actuators Provide Long Lifetime

Highest possible reliability is assured by the use of award-winning PICMA® multilayer piezo actuators. PICMA® actuators are the only actuators on the market with ceramic-only insulation, which makes them resistant to ambient humidity and leakage-current failures. They are thus far superior to conventional actuators in reliability and lifetime.

System properties	
System configuration	P-612.2 SL and E-500 modular system with E-503 amplifier and E-509 sensor module, 100 load
Amplifier bandwidth, small signal	45 Hz
Settling time (10 % step width)	15 ms



P-612.2 dimensions in mm

P-612 are available as XY-scanners (P-612.2SL, on the left) and vertical stages (P-612.ZSL, on the right) providing a travel range of 100 µm per axis

Technical Data

Model	P-612.2SL	P-612.20L	Units	Tolerance
Active axes	X, Y	X, Y		
Motion and positioning				
Integrated sensor	SGS	–		
Open-loop travel, -20 to +120 V	130	130	µm	min. (+20 %/-0 %)
Closed-loop travel	100	–		µm
Open-loop resolution	0.8	0.8	nm	typ.
Closed-loop resolution	5	–	nm	typ.
Linearity 0.4		–	%	typ.
Repeatability	<10	–	nm	typ.
Pitch	±10	±10	µrad	typ.
Yaw in X/ Y	±10 / ±50	±10 / ±50	µrad	typ.
Mechanical properties				
Stiffness	0.15	0.15	N/µm	±20 %
Unloaded resonant frequency	400	400	Hz	±20 %
Resonant frequency @ 100 g	200	200	Hz	±20 %
Push/pull force capacity in motion direction	15 / 5	15 / 5	N	Max.
Load capacity	15	15	N	Max.
Drive properties				
Ceramic type	PICMA® P-885	PICMA® P-885		
Electrical capacitance	1.5	1.5	µF	±20 %
Dynamic operating current coefficient	1.9	1.9	µA/(Hz • µm)	±20 %
Miscellaneous				
Operating temperature range	-20 to 80	-20 to 80	°C	
Material	Aluminum, steel	Aluminum, steel		
Mass	105	105	g	±5 %
Cable length	1.5	1.5	m	±10 mm
Sensor connector	LEMO connector	–		
Voltage connection	LEMO connector	LEMO connector		

Resolution of PI Piezo Nanopositioners is not limited by friction or stiction. Noise equivalent motion with E-503 amplifier (p. 2-146)
Recommended controller
Single-channel (1 per axis): E-610 servo-controller / amplifier (p. 2-110) , E-625 servo-controller, bench-top (p. 2-114), E-621 controller module (p. 2-160)
Multi-channel: modular piezo controller system E-500 (p. 2-142) with amplifier module E-503 (three channels) (p. 2-146) or E-505 (1 per axis, high-power) (p. 2-147) and E-509 controller (p. 2-152)

P-545 PI nano™ XY Piezo Stage for SR Microscopy

Low-Profile, Low-Cost Nanopositioning Systems for Super-Resolution Microscopy

PI nano™ series nanopositioning stages feature a very low profile of 20 mm (0.8), a large aperture for 3 x 1'' slides and deliver highly accurate motion with sub-nanometer resolution Slide / petri dish holders optional

- **Low Profile for Easy Integration: 20 mm (0.8")**
- **XY and XYZ Versions 200 µm Travel Range**
- **Large Clear Aperture for 3 x 1" Slides**
- **Recessed Sample Holders for Maximized Utility Available**
- **Outstanding Lifetime Due to PICMA®Piezo Actuators**
- **Cost-Effective Design due to Piezoresistive Sensors**
- **Compatible w/ Leading Image Acquisition Software Package**
- **Closed-Loop Control for High Repeatability and Accuracy**
- **Millisecond Step Time, Ideal for Super-Resolution Microscopy**
- **24-Bit Controller w/ USB, Ethernet, RS-232 Interface and Analog Control**
- **Available Manual Long-Travel Stage with Motor Upgrade Option**

Long Travel, Low Profile, Optimized for Microscopy

PI nano™ XY and XYZ low-profile piezo scanning stages are optimized for easy integration into high-resolution microscopes. They feature a very low profile of 20 mm (0.8") and a large aperture designed to hold Petri dishes and standard slide holders. The long travel ranges of up to 200 x 200 x 200 µm with nanometer closed-loop resolution are ideal for leading-edge microscopy and imaging applications.

Cost Effective Design, High Performance

PI nano™ series piezo positioning stages are designed to provide high performance at minimum cost. For highly-stable, closed loop operation, piezoresistive sensors are applied directly to the moving structure and precisely measure the displacement of the stage platform. The very high sensitivity of these sensors provides optimum position stability and responsiveness as well as nanometer resolution. A proprietary servo controller significantly improves the motion linearity compared to conventional piezoresistive sensor controllers.

High Reliability and Long Lifetime

The compact P-545 systems are equipped with preloaded PICMA® high-performance piezo actuators which are integrated into a sophisticated, FEA-modeled, flexure guiding system. The PICMA® actuators feature cofired ceramic encapsulation and provide better performance and reliability than conventional piezo actuators. Actuators, guidance and sensors are maintenance-free, not subject to wear and offer extraordinary reliability.

Application Examples

- Super-resolution microscopy
- 3D Imaging
- Laser technology
- Interferometry
- Metrology
- Biotechnology
- Screening
- Micromanipulation

Ordering Information

P-545.2R7
Plnano™ XY Piezo Stage, Slide-Size Aperture, 200 x 200 µm, Piezoresistive Sensors, with USB Controller

Controller included

E-545.3RD
Plnano™ Multi-Channel Piezo Controller with High-Speed Digital Interface, 3 Channels, Piezoresistiv Sensors, Sub-D Connectors

Accessories

M-545.2MO
XY Microscope Stage, 25 x 25 mm, Micrometer-Driven, High Stability, Compatible with PI® Piezo Stages, for Olympus Microscopes

M-545.2MN
XY Microscope Stage, 25 x 25 mm, Micrometer-Driven, High Stability, Compatible with PI® Piezo Stages, for Nikon Microscopes

M-545.2ML
XY Microscope Stage, 25 x 25 mm, Micrometer-Driven, High Stability, Compatible with PI® Piezo Stages, for Leica Microscopes

M-545.2MZ
XY Microscope Stage, 25 x 25 mm, Micrometer-Driven, High Stability, Compatible with PI® Piezo Stages, for Zeiss Microscope

P-545.PD3
35mm Petri Dish Holder for P-545 Plnano™ Piezo Stages

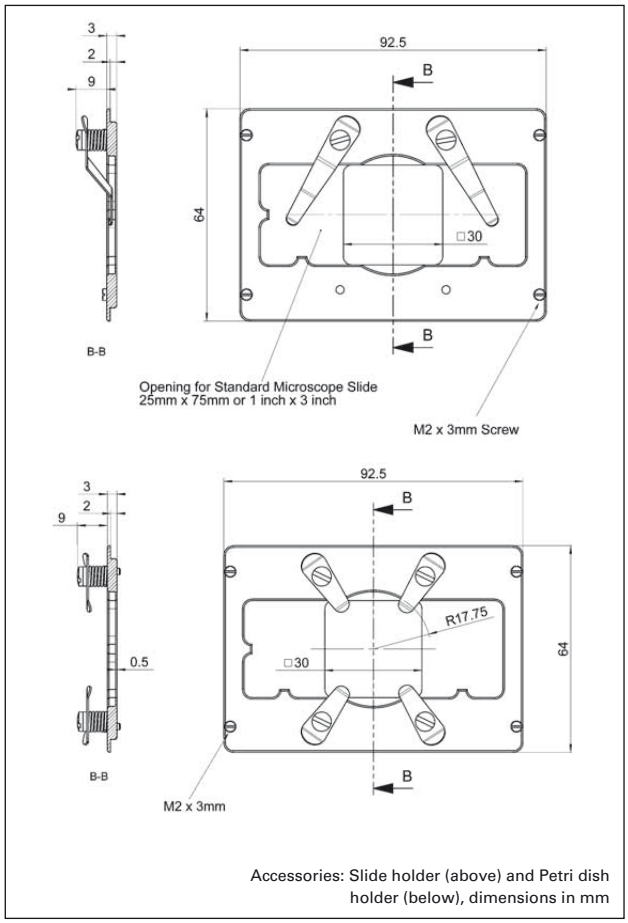
P-545.SH3
Microscope Slide Holder for Plnano™ Piezo Stages

P-545.PP3
Plain Plate for Accessories for Plnano™ Piezo Stages

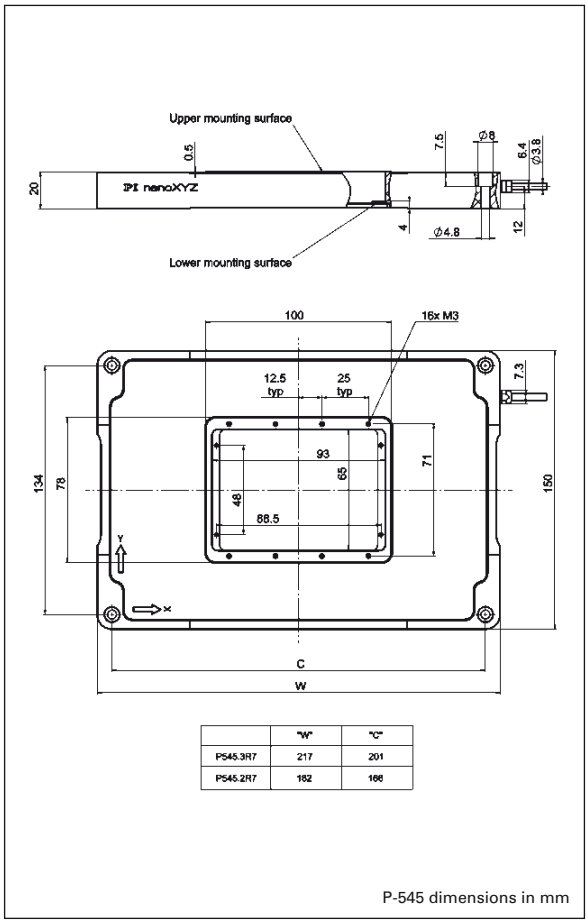
Additional accessories on request.

Background: the piezo controller is included and comes with a 24-bit resolution USB port as well as ethernet, RS-232 and analog interface. Foreground: The optional M-545 manual XY stage provides a stable platform for the PI nano™ piezo stages. Custom stage version shown

Capacitive Sensor Version and High Speed Tracking Version also Available



Accessories: Slide holder (above) and Petri dish holder (below), dimensions in mm



	"W"	"C"
P545.3R7	217	201
P545.2R7	182	166

P-545 dimensions in mm

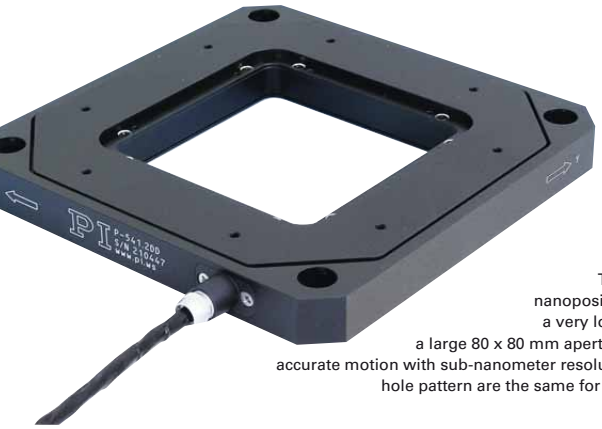
Technical Data

Model	P-545.2R7	Unit	Tolerance
Active axes	X, Y		
Motion and positioning			
Integrated sensor	piezoresistive		
Closed-loop travel	200 x 200	µm	
Closed-loop resolution*	1	nm	typ.
Linearity	±0.1	%	typ.
Repeatability	< 5	nm	typ.
Mechanical properties			
Push/pull force capacity	100 / 30	N	max.
Load	50	N	max.
Drive properties			
Ceramic type	PICMA® P-885		
Electrical capacitance	6	µF	±20%
Miscellaneous			
Operating temperature range	-20 to 80	°C	
Material	Aluminum		
Mass	1	kg	±5%
Cable length	1.5	m	±10 mm
Sensor / voltage connection	Sub-D, 25 pin		
Piezo controller (included in delivery)	E-545		

* Resolution of PI Piezo Nanopositioners is not limited by friction or stiction. Value given is noise equivalent motion measured v

P-541.2 – P-542.2 Piezo XY-Stage

Low-Profile XY Nanopositioning System with Large Aperture



The P-541/P-542-series nanopositioning stages feature a very low profile of 16.5 mm, a large 80 x 80 mm aperture and deliver highly accurate motion with sub-nanometer resolution. Dimensions and hole pattern are the same for all P-541/P-542 stages

- **Low Profile for Easy Integration: 16.5 mm; 80 x 80 mm Clear Aperture**
- **Up to 200 x 200 µm Travel Range**
- **Parallel-Kinematics / Metrology for Enhanced Responsiveness & Multi-Axis Precision**
- **High-Dynamics Direct-Drive Version**
- **Choice of Sensors: Strain Gauge (Lower Cost) or Capacitive Sensors (Higher Performance)**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**
- **Combination with Long Travel Microscopy Stages or Longer Stroke**

Low Profile, Optimized for Microscopy Applications

P-541/P-542 nanopositioning and scanning stages are designed for easy integration into high-resolution microscopes. They feature a very low profile of 16.5 mm, a large 80 x 80 mm aperture, and offer highly accurate motion with sub-nanometer resolution.
A variety of Z stages and Z-tip/tilt stages with the same footprint are also offered to suit a wide range of applications (p. 2-44). They are ideal for alignment, nano-focusing or metrology tasks.

Choice of Drives: Long Range or High-Speed Direct Drive

Lever-amplified XY systems with 100 and 200 µm travel and direct-driven XY scanners with 45 µm travel are available. Their high resonant frequencies of 1.5 kHz in both axes allow for faster step response and higher scanning rates, needed for example in single-molecule microscopy, or in other time-critical applications.

Parallel Kinematics for Fast Response

In a parallel kinematics multi-axis system, all actuators act directly on one moving platform. This means that all axes move the same minimized mass and can be designed with identical dynamic properties. Systems with parallel kinematics and metrology have additional advantages over serially stacked or nested systems, including more-compact construction and no cumulative error from the different axes. Parallel kinematics systems can be operated with up to six degrees of freedom with low inertia and excellent dynamic performance. Multi-axis nanopositioning systems equipped with both parallel kinematics and parallel, direct metrology are able to measure platform position in all degrees of freedom against one common fixed reference. In such systems, undesirable motion from one actuator in the direction of another (cross talk) is detected immediately and actively compensated by the servo-loops.

Tailored Position Measurement

Integrated high-resolution position sensors provide fast response and positional stability in the nanometer range. Top-of-the-line models use capacitive sensors. They measure displacement directly and without physical contact (direct metrology) enabling superior linearity. Alternatively, versions with cost-effective strain gauge sensors (SGS) are also available.

Application Examples

- Laser technology
- Scanning microscopy
- Mask / wafer positioning
- Interferometry
- Metrology
- Biotechnology
- Micromanipulation

Ordering Information

P-541.2DD
XY Nanopositioning System with Large Aperture, High-Speed Direct Drive, 45 x 45 µm, Parallel Kinematics, Capacitive Sensors

P-541.2CD
XY Nanopositioning System with Large Aperture, 100 x 100 µm, Parallel Kinematics, Capacitive Sensors

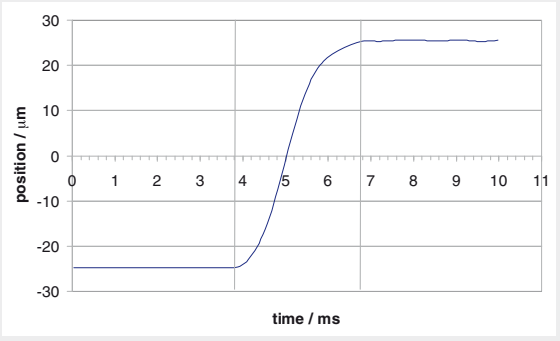
P-542.2CD / P-542.2CL
XY Nanopositioning System with Large Aperture, 200 x 200 µm, Parallel Kinematics, Capacitive Sensors

P-541.2SL
XY Nanopositioning System with Large Aperture, 100 x 100 µm, Strain Gauge Sensors

P-542.2SL
XY Nanopositioning System with Large Aperture, 200 x 200 µm, Strain Gauge Sensors

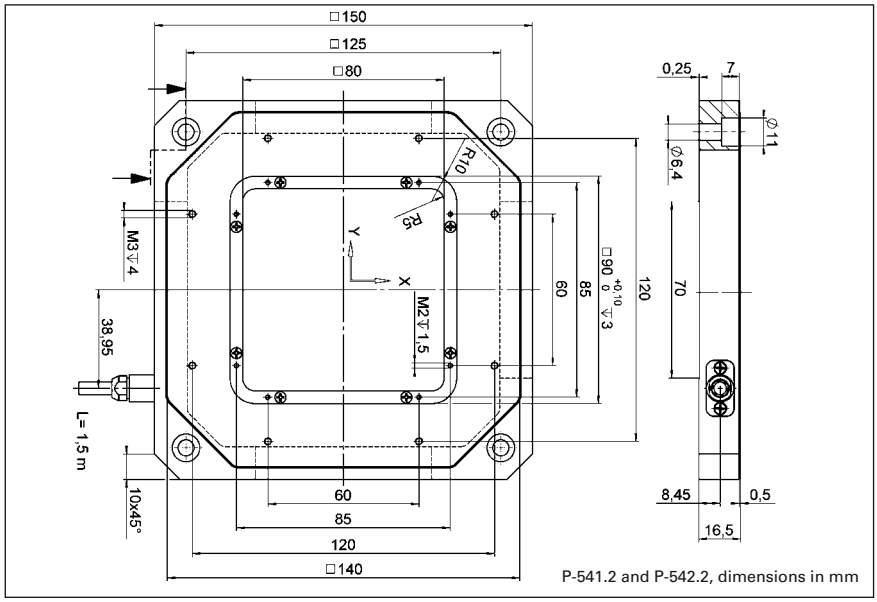
P-541.20L
XY Nanopositioning System with Large Aperture, 100 x 100 µm, Open Loop

P-542.20L
XY Nanopositioning System with Large Aperture, 200 x 200 µm, Open Loop



The settling time of a P-541.2DD stage is only 3 ms for a 50 µm step

System properties	
System configuration	P-541.2CD and E-500 modular system with E-503 amplifier and E-509 sensor module, 200 g load
Amplifier bandwidth, large signal	35 Hz
Settling time (full travel)	28 ms



P-541.2 and P-542.2, dimensions in mm

Technical Data

Model	P-541.2CD	P-542.2CD P-542.2CL	P-541.2DD	P-541.2SL	P-542.2SL	P-541.20L	P-542.20L	Units	Tolerance
Active axes	X, Y	X, Y	X, Y	X, Y	X, Y	X, Y	X, Y		
Motion and positioning									
Integrated sensor	Capacitive	Capacitive	Capacitive	SGS	SGS	–	–		
Open-loop travel, -20 to +120 V	175 x 175	290 x 290	60 x 60	175 x 175	290 x 290	175 x 175	290 x 290	µm	min. (+20 %/0 %)
Closed-loop travel	100 x 100	200 x 200	45 x 45	100 x 100	200 x 200	–	–	µm	
Open-loop / closed-loop resolution	0.2 / 0.3	0.4 / 0.7	0.1 / 0.3	0.2 / 2.5	0.4 / 4	0.2 / –	0.4 / –	nm	typ.
Linearity	0.03	0.03	0.03*	0.2	0.2	–	–	%	typ.
Repeatability	<5	<5	<5	<10	<10	–	–	nm	typ.
Pitch	<±5	<±5	<±3	<±5	<±5	<±5	<±5	µrad	typ.
Yaw	<±10	<±10	<±3	<±10	<±10	<±10	<±10	µrad	typ.
Mechanical properties									
Stiffness in motion direction	0.47	0.4	10	0.47	0.4	0.47	0.4	N/µm	±20 %
Unloaded resonant frequency	255	230	1550	255	230	255	230	Hz	±20 %
Resonant frequency @ 100 g	200	190	–	200	190	200	190	Hz	±20 %
Resonant frequency @ 200 g	180	–	1230	180	–	180	–	Hz	±20 %
Resonant frequency @ 300 g	150	145	–	150	145	150	145	Hz	±20 %
Push/pull force capacity in motion direction	100 / 30	100 / 30	100 / 30	100 / 30	100 / 30	100 / 30	100 / 30	N	Max.
Load capacity	20	20	20	20	20	20	20	N	Max.
Drive properties									
Ceramic type	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885		
Electrical capacitance per axis	4.2	7.5	9	4.2	7.5	4.2	7.5	µF	±20 %
Dynamic operating current coefficient per axis	5.2	4.8	25	5.2	4.8	5.2	4.8	µA/(Hz•µm)	±20 %
Miscellaneous									
Operating temperature range	20 to 80	20 to 80	20 to 80	-20 to 80	-20 to 80	-20 to 80	-20 to 80	°C	
Material	Aluminum	Aluminum	Aluminum	Aluminum	Aluminum	Aluminum	Aluminum		
Mass	1100	1150	1210	1050	1100	1050	1100	g	±5 %
Cable length	1.5	1.5	1.5	1.5	1.5	1.5	1.5	m	±10 mm
Sensor connection	Sub-D Special	Sub-D Special / LEMO	Sub-D Special	LEMO	LEMO	–	–		
Voltage connection	Sub-D Special	Sub-D Special / LEMO	Sub-D Special	LEMO	LEMO	LEMO	LEMO		

Resolution of PI Piezo Nanopositioners is not limited by friction or stiction. Value given is noise equivalent motion with E-503 (p. 2-146) or E-710 controller (p. 2-128).
Dynamic Operating Current Coefficient in µA per Hz and µm. Example: Sinusoidal scan of 10 µm at 10 Hz requires approximately 0.48 mA drive current for the P-542.2CD.
*With digital controller. Non-linearity of direct drive stages measured with analog controllers is up to 0.1 % typ.
Recommended controller / amplifier
Single-channel (1 per axis): E-610 servo controller / amplifier (p. 2-110), E-625 servo controller, bench-top (p. 2-114), E-621 controller module (p. 2-160)
Multi-channel: modular piezo controller system E-500 (p. 2-142) with amplifier module E-503 (three channels) (p. 2-146) or E-505 (1 per axis, high-power) (p. 2-147) and E-509 controller (p. 2-152) (for systems with sensors)
Multi-channel digital controllers: E-710 bench-top (p. 2-128), E-712 modular (p. 2-140), E-725 high-power (p. 2-126), E-761 PCI board (p. 2-130)

P-734 XY Piezo Scanner

High-Dynamics System with Minimum Runout & Clear Aperture

P-734 low-bow flexure nanopositioning stage with ultra-precise trajectory control

- **Ultra-Precision Trajectory Control, Ideal for Surface Analysis and Scanning Microscopy**
- **Parallel-Kinematics / Metrology for Enhanced Responsiveness / Multi-Axis Precision**
- **Travel Range 100 x 100 µm, Clear Aperture 56 x 56 mm**
- **Capacitive Sensors for Resolution <0,4 nm**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**

P-734 high-dynamics, XY piezo nanopositioning stages feature linear travel ranges to 100 x 100 µm with sub-nanometer resolution and maximum flatness of motion.

Flatness in the Low Nanometer Range

P-734 open-frame XY nanopositioning and scanning stages are ideal for nanometrology tasks that require extreme flatness of scanning. These stages feature an ultra-precise, flexure guiding system which confines motion to the XY plane and reduces runout in Z to a few nanometers or less. This unsurpassed trajectory precision is fundamental for highest-precision surface metrology applications. These stages provide a positioning and scanning range of 100 x 100 µm with accuracy and resolution in the nanometer and sub-nanometer range.

Application Examples

- Scanning microscopy
- Metrology / interferometry
- Semiconductor testing
- Mask/wafer positioning
- Image processing / stablilization
- Biotechnology
- Micromanipulation
- Nanopositioning

Excellent Guiding Accuracy

Flexures optimized with Finite Element Analysis (FEA) are used to guide the stage. FEA techniques are used to give the design the highest possible stiffness in, and perpendicular to, the direction of motion, and to minimize linear and angular runout. Flexures allow extremely high-precision motion, no matter how minute, as they are completely free of play and friction.

Higher Precision in Periodic Motion

The highest dynamic accuracy in scanning applications is made possible by the DDL algorithm, which is available in PI's modern digital controllers. DDL eliminates tracking errors, improving dynamic linearity and usable bandwidth by up to three orders of magnitude!

Direct Position Measurement with Sub-Nanometer Accuracy

PI's proprietary capacitive sensors measure position directly and without physical contact. They are free of friction and hysteresis, a fact which, in combination with the positioning resolution of well under 1 nm, makes it possible to achieve very high levels of linearity. A further advantage of direct metrology with capacitive sensors is the high phase fidelity and the high bandwidth of up to 10 kHz.

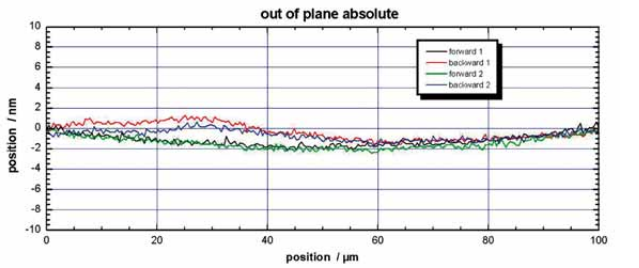
Parallel Kinematics and Metrology with Capacitive Sensors for High Trajectory Fidelity

In a parallel kinematics multi-axis system, all actuators act directly on one moving platform. This means that all axes move the same minimized mass and can be designed with identical dynamic properties. Systems with parallel kinematics and metrology have additional advantages over serially stacked or nested systems, including more-compact construction and no cumulative error from the different axes. Parallel kinematics systems can be operated with up to six degrees of freedom with low inertia and excellent dynamic performance. Multi-axis nanopositioning systems equipped with both parallel kinematics and parallel, direct metrology are able to measure platform position in all degrees of freedom against one common fixed reference. In such systems, undesirable motion from one actuator in the direction of another (cross talk) is detected immediately and actively compensated by the servo-loops. This Active Trajectory Control Concept can keep deviation from a trajectory to under a few nanometers, even in dynamic operation.

Ordering Information

P-734.2CD
High-Precision XY Nanopositioning System with Minimum Runout, 100 x 100 µm, Capacitive Sensors, Parallel Metrology, Sub-D Connector

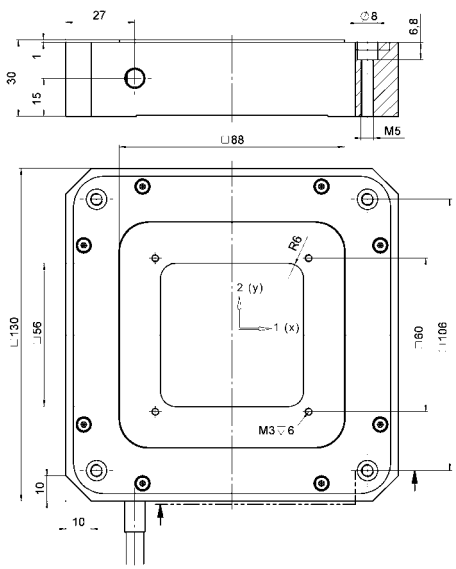
P-734.2CL
High-Precision XY Nanopositioning System with Minimum Runout, 100 x 100 µm, Capacitive Sensors, Parallel Metrology, LEMO Connector



Typical flatness of P-734 motion is in the low nanometer range

Ceramic Insulated Piezo Actuators Provide Long Lifetime

Highest possible reliability is assured by the use of award-winning PICMA ® multilayer piezo actuators. PICMA ® actuators are the only actuators on the market with ceramic-only insulation, which makes them resistant to ambient humidity and leakage-current failures. They are thus far superior to conventional actuators in reliability and lifetime.



P-734 dimensions in mm

Technical Data

Model	P-734.2CL	P-734.2CD	Units	Tolerance
Active axes	X, Y	X, Y		
Motion and positioning				
Integrated sensor	Capacitive	Capacitive		
Open-loop travel, -20 to +120 V	110 x 110	110 x 110	µm	min. (+20 %/-0 %)
Closed-loop travel	100 x 100	100 x 100	µm	
Open-loop resolution	0.2	0.2	nm	typ.
Closed-loop resolution	0.3	0.3	nm	typ.
Linearity	0.03	0.03	%	typ.
Repeatability	<2.5	<2.5	nm	typ.
Pitch	<3	<3	µrad	typ.
Yaw	<10	<10	µrad	typ.
Flatness	<5	<5	nm	typ.
Mechanical properties				
Stiffness	3	3	N/µm	±20 %
Unloaded resonant frequency	500	500	Hz	±20 %
Resonant frequency @ 200 g	350	350	Hz	±20 %
Resonant frequency @ 500 g	250	250	Hz	±20 %
Push/pull force capacity in motion direction	300 / 100	300 / 100	N	Max.
Load capacity	20	20	N	Max.
Drive properties				
Ceramic type	PICMA® P-885	PICMA® P-885		
Electrical Capacitance	6.2	6.2	µF	±20%
Dynamic operating current coefficient	7.8	7.8	µA/(Hz • µm)	±20%
Miscellaneous				
Operating temperature range	-20 to 80	-20 to 80	°C	
Material	Aluminum	Aluminum		
Mass (with cables)	1.04	1.04	kg	±5 %
Cable length	1.5	1.5	m	±10 mm
Sensor connection	2x LEMO	Sub-D Special		
Voltage connection	4x LEMO	Sub-D Special		

Dynamic Operating Current Coefficient in µA per Hz and µm. Example: Sinusoidal scan of 10 µm at 10 Hz requires approximately 7.8 mA drive current.

Recommended controller / amplifier
P-734.2CL (p. 2-64): E-500 modular piezo controller system (p. 2-142) with amplifier module E-503 (three channels) (p. 2-146) or E-505 (1 per axis, high performance) (p. 2-147) and E-509 controller (p. 2-152)
P-734.2CD (p. 2-64): Multi-channel digital controllers: E-710/E-725 bench-top (p. 2-128, p. 2-126), E-712 modular (p. 2-140), E-761 PCI board (p. 2-130)

P-517 · P-527 Multi-Axis Piezo Scanner

High-Dynamics Nanoscanner for Scanning Probe Microscopy

P-527.2CL parallel-kinematic nanopositioning system

- **Travel Ranges to 200 µm**
- **Sub-Nanometer Resolution**
- **Frictionless, High-Precision Flexure Guiding System**
- **Capacitive Sensors for Highest Linearity**
- **Parallel-Kinematics / Metrology for Enhanced Responsiveness / Multi-Axis Precision**
- **Clear Aperture 66 x 66 mm**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**

P-517 and P-527 high-dynamics, multi-axis piezo-nanopositioning stages are available in XY ΘZ, XY and XYZ configurations featuring linear travel ranges to 200 x 200 x 20 µm and rotation ranges to 4 mrad. The 66 x 66 mm clear aperture is ideal for transmitted-light applications.
Z/tip/tilt versions in the same form factor are also offered as models P-518, P-528, P-558 (see p. 2-46) and as custom versions with up to six degrees of freedom.

Capacitive Sensors for Highest Accuracy

PI's proprietary capacitive sensors measure position directly and without physical contact. They are free of friction and hysteresis, a fact which, in combination with the positioning resolution of well under 1 nm, makes it possible to achieve very high levels of linearity. A further advantage of direct metrology with capacitive sensors is the high phase fidelity and the high bandwidth of up to 10 kHz.

Application Examples

- Metrology
- Interferometry
- Optics
- Lithography
- Nanopositioning
- Scanning microscopy
- Mass storage device testing
- Laser technology
- Micromachining

Technical Data

Model	P-517.2CL	P-527.2CL	P-517.3CL/ P-517.3CD	P-527.3CL/ P-527.3CD	P-517.RCD	P-527.RCD
Active axes	X, Y	X, Y	X, Y, Z	X, Y, Z	X, Y, θ_z	X, Y, θ_z
Motion and positioning						
Integrated sensor	Capacitive	Capacitive	Capacitive	Capacitive	Capacitive	Capacitive
Open-loop travel, -20 to +120 V	130	250	130; Z: 25	250; Z: 25	130; θ_z: ±1.3 mrad	250; θ_z: ±2.5 mrad
Closed-loop travel	100	200	100; Z: 20	200; Z: 20	100; θ_z: ± 1 mrad	200; θ_z: ± 2 mrad
Open-loop resolution	0.3	0.5	0.3; Z: 0.1	0.5; Z: 0.1	0.3; θ_z: ±0.1 µrad	0.5; θ_z: ±0.1 µrad
Closed-loop resolution	1	2	1; Z: 0.1	2; Z: 0.1	1; θ_z: ±0.3 µrad	2; θ_z: ±0.3 µrad
Linearity	0.03	0.03	0.03	0.03	0.03	0.03
Repeatability	±5	±10	±5; Z: ±1	±10; Z: ±1	±5; θ_z: ±0.5 µrad	±10; θ_z : ±1 µrad
Mechanical properties						
Stiffness	2	1	2; Z: 15	1; Z: 15	2	1
Unloaded resonant frequency	450	350	450; Z: 1100	350; Z: 1100	450; θ_z: 400	350; θ_z: 300
Resonant frequency @ 500 g X, Y	250	190	250	190	250	190
Resonant frequency @ 2500 g X, Y	140	110	140	110	140	110
Push/pull force capacity in motion direction	50 / 30	50 / 30	50 / 30	50 / 30	50 / 30	50 / 30
Drive properties						
Ceramic type	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885
Electrical capacitance	9.2	9.2	9; Z: 6	9; Z: 6	9	9
Dynamic operating current coefficient (DOCC)	11.5	5.8	11.5; Z: 37	5.5; Z: 37	11.5	5.5
Miscellaneous						
Operating temperature range	-20 to 80	-20 to 80	-20 to 80	-20 to 80	-20 to 80	-20 to 80
Material	Aluminum	Aluminum	Aluminum	Aluminum	Aluminum	Aluminum
Mass	1.4	1.4	1.45	1.45	1.4	1.4
Sensor / voltage connection	LEMO	LEMO	Sub-D special (CD-version) LEMO (CL-version)	Sub-D special (CD-version) LEMO (CL-version)	Sub-D Special	Sub-D Special

Resolution of PI Piezo Nanopositioners is not limited by friction or stiction. Value given is noise equivalent motion with E -503 or E-710 controller (p. 2-146 or p. 2-128)
Linear Dynamic Operating Current Coefficient in µA per Hz and µm. Example for P-527.2xx: Sinusoidal scan of 30 µm at 10 Hz requires approximately 1.8 mA drive current (p. 2-70). Electrical capacitance and DOCC of the rotation axes base upon differential motion in X, Y; therefore not stated.
Recommended controller
Versions with LEMO connectors: Single-channel (1 per axis): E-610 servo-controller / amplifier (p. 2-110), E-625 servo-controller, bench-top (p. 2-114), E-621 controller module (p. 2-160) Multi-channel: modular piezo controller system E-500 (p. 2-142) with amplifier module E-503 (three channels) (p. 2-146) or E-505 (1 per axis, high-power) (p. 2-147) and E-509 controller (p. 2-152)
Versions with Sub-D connectors: Multi-channel digital controllers: E-710 bench-top (p. 2-128), E-712 modular (p. 2-140), E-725 high-power (p. 2-126), E-761 PCI board (p. 2-130)

Active and Passive Guidance for Nanometer Flatness and Straightness

Flexures optimized with Finite Element Analysis (FEA) are used to guide the stage. The FEA techniques provide for the highest possible stiffness in, and perpendicular to, the direction of motion, and minimize linear and angular runout. Flexures allow extremely high-precision motion, no matter how minute, as they are completely free of play and friction. Due to the parallel kinematics design there is only one common moving platform for all axes, minimizing mass, enabling identical dynamic behavior and eliminating cumulative errors. Parallel kinematics also allows for a more compact construction and faster response compared to stacked or nested designs. The high precision due to flexure guidance is further enhanced by Active Trajectory Control: Multi-axis nanopositioning systems equipped with both parallel kinematics and parallel direct metrology are able to measure platform position in all degrees of freedom against one common fixed reference. In such systems, undesirable motion from one actuator in the direction of another (cross-talk) is detected immediately and actively compensated by the servo-loops. This Active Trajectory Control Concept can keep deviation from a trajectory to under a few nanometers, even in dynamic operation.

Ceramic Insulated Piezo Actuators Provide Long Lifetime

Highest possible reliability is assured by the use of award-winning PICMA® multilayer piezo actuators. PICMA® actuators are the only actuators on the market with ceramic-only insulation, which makes them resistant to ambient humidity and leakage-current failures. They are thus far superior to conventional actuators in reliability and lifetime.

	Units	Tolerance
	µm	min.(+20%/0%)
	µm	
	nm	typ.
	nm	typ.
	%	typ.
	nm	typ.
	N/µm	±20%
	Hz	±20%
	Hz	±20%
	Hz	±20%
	N	Max.
	µF	±20%
	µA/(Hz • µm)	±20%
	°C	
	kg	±5%

Ordering Information

P-517.2CL
Precision XY Nanopositioning System, 100 x 100 µm, Capacitive Sensors, Parallel Metrology, LEMO Connector

P-527.2CL
Precision XY Nanopositioning System, 200 x 200 µm, Capacitive Sensors, Parallel Metrology, LEMO Connector

P-517.3CL
Precision XYZ Nanopositioning System, 100 x 100 x 20 µm, Capacitive Sensors, Parallel Metrology, LEMO Connector

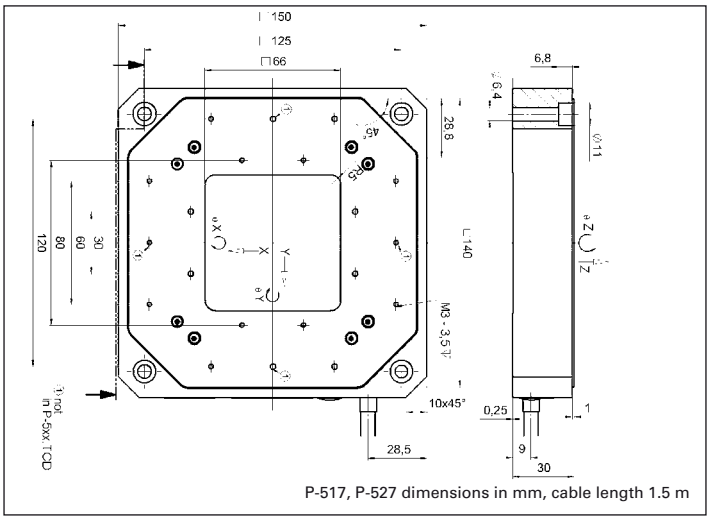
P-517.3CD
Precision XYZ Nanopositioning System, 100 x 100 x 20 µm, Capacitive Sensors, Parallel Metrology, Sub-D Connector

P-527.2CL
Precision XY Nanopositioning System, 200 x 200 µm, Capacitive Sensors, Parallel Metrology, LEMO Connector

P-527.3CD
Precision XYZ Nanopositioning System, 200 x 200 x 20 µm, Capacitive Sensors, Parallel Metrology, Sub-D Connector

P-517.RCD
Precision XY / Rotation Nanopositioning System, 100 x 100 µm, 2 mrad, Capacitive Sensors, Parallel Metrology, Sub-D Connector

P-527.RCD
Precision XY / Rotation Nanopositioning System, 200 x 200 µm, 4 mrad, Capacitive Sensors, Parallel Metrology, Sub-D Connector



P-517, P-527 dimensions in mm, cable length 1.5 m

P-733.2 · P-733.3 XY(Z) Piezo-Nanopositioning Stage

High-Precision XY(Z) Scanner Family with Aperture

P -733.3 DD (left) and P -733.2 DD, high-speed, direct drive XY(Z) scanning stages are the fastest scanning stages with large aperture currently available (2.2 kHz resonant frequency!). Both units feature a footprint of only 100 x 100 mm. CD for size comparison.

- **Travel Ranges to 100 x 100 µm in X,Y & to 10 µm in Z**
- **Resolution to 0.1 nm with Capacitive Sensors**
- **High-Speed Versions with Direct Drive**
- **Vacuum and Non-Magnetic Versions**
- **Parallel Kinematics for Better Multi-Axis Accuracy and Dynamics**
- **Parallel Metrology for Active Trajectory Control**
- **Frictionless, High-Precision Flexure Guiding System**
- **Clear Aperture 50 x 50 mm for Transmitted-Light Applications**

P-733 XY and XYZ piezo driven stages are fast and highly accurate nanopositioning and scanning systems. They provide a positioning and scanning range of 100 x 100 (x10) µm together with sub-nanometer resolution and are equipped with parallel-metrology capacitive position feedback for superior multi-axis linearity and repeatability. The guiding accuracy minimizes runout to under 10 nm over the whole travel range. In addition, the high-speed Z-axis of the P-733.3CD can actively compensate any out-of-plane Z-axis deviation during XY motion.

Application Examples

- Image processing / stablilization
- Scanning microscopy
- Surface inspection
- Metrology / interferometry
- Biotechnology
- Semiconductor testing
- Mask / wafer positioning
- Micromanipulation
- Nanopositioning with high flatness & straightness

Fastest Multi-Axis Systems / Direct Drive, Low Profile and Large Apertures

P-733.2DD / .3DD multi-axis piezo nanopositioning systems are the fastest ultra-high-precision, open-frame stages for scanning microscopy. They provide a positioning and scanning range of 30 x 30 (x10) µm. P-733 nanopositioning and scanning stages feature very low profiles, as low as 20 mm (0.8 inch). The novel, high-stiffness direct drive gives the systems resonant frequencies as high as 2.2 kHz (4 x that of other comparable systems), enabling millisecond scanning rates with sub-nanometer resolution.

Parallel-Kinematics / Metrology for Enhanced Responsiveness

In a parallel kinematics multi-axis system, all actuators act directly on one moving platform. This means that all axes move the same minimized mass and can be designed with identical dynamic properties. Multi-axis nanopositioning systems equipped with both parallel kinematics and parallel, direct metrology are able to measure platform position in all degrees of freedom against one common fixed reference. In such systems, undesirable motion from one actuator in the direction of another (cross talk) is detected immediately and actively compensated by the servo-loops.

Capacitive Sensors for Subnanometer Resolution

PI's proprietary capacitive sensors measure position directly and without physical contact. They are free of friction and hysteresis, a fact which, in combination with the positioning resolution of well under 1 nm, makes it possible to achieve very high levels of linearity. A further advantage of direct metrology with capacitive sensors is the high phase fidelity and the high bandwidth of up to 10 kHz. The closed-loop resolution is 0.3 nm for the X and Y axes and 0.2 nm for the optional Z-axis. The direct drive versions are rated to 0.1 nm resolution for every axis.

Large Variety of Models for a Broad Range of Applications

For Z-axis scanning applications, the P-733.ZCD (see p. 2-42) version is available with a travel range of 100 µm. For ultra-high-vacuum applications down to 10^{-9} hPa, nanopositioning systems as well as comprehensive accessories, such as suitable feedthroughs, are available.

Ordering Information

P-733.2DD
High-Dynamics High-Precision XY Nanopositioning System, 30 x 30 µm, Direct Drive, Capacitive Sensors, Parallel Metrology, Sub-D Connector

P-733.3DD
High-Dynamics Precision XYZ Nanopositioning System, 30 x 30 x 10 µm, Direct Drive, Capacitive Sensors, Parallel Metrology, Sub-D Connector

P-733.2CD* / P-733.2CL*
High-Precision XY Nanopositioning System, 100 x 100 µm, Capacitive Sensors, Parallel Metrology

P-733.3CD* / P-733.3CL*
Precision XYZ Nanopositioning System, 100 x 100 x 10 µm, Capacitive Sensors, Parallel Metrology

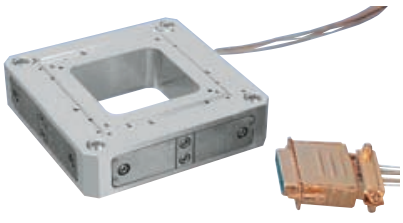
P-733.2VL* / P-733.2VD*
High-Precision XY Nanopositioning System, 100 x 100 µm, Capacitive Sensors, Parallel Metrology, Vacuum Compatible to 10-6 hPa

P-733.2UD
High-Precision XY Nanopositioning System, 100 x 100 µm, Capacitive Sensors, parallel metrology, Sub-D Connector, Vacuum Compatible to 10-9 hPa

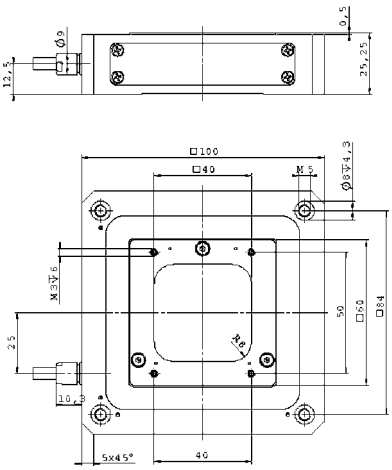
*.xxD with Sub-D Connector

*.xxL with LEMO Connector

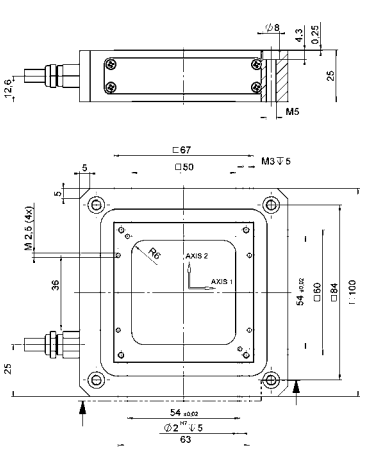
Ask about custom designs



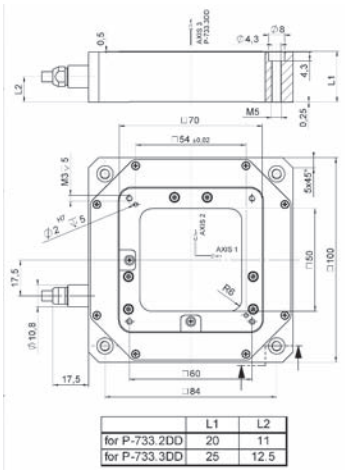
P-733.2UD non-magnetic XY scanning stage for UHV to 10^{-9} hPa



P-733.3 dimensions in mm



P-733.2 dimensions in mm



P-733.xDD dimensions in mm

Technical Data

Model	P-733.2CD P-733.2CL	P-733.3CD P-733.3CL	P-733.2DD	P-733.3DD	Units	Tolerance
Active axes	X, Y	X, Y, Z	X, Y	X, Y, Z		
Motion and positioning						
Integrated sensor	Capacitive	Capacitive	Capacitive	Capacitive		
Open-loop travel, -20 to +120 V	115 x 115	115 x 115 x 12	33 x 33	33 x 33 x 14	µm	min. (+20 %/-0 %)
Closed-loop travel	100 x 100	100 x 100 x 10	30 x 30	30 x 30 x 10	µm	
Open-loop resolution	0.2	0.2 (0.1 in Z)	0.1	0.1	nm	typ.
Closed-loop resolution	0.3	0.3 (0.2 in Z)	0.1	0.1	nm	typ.
Linearity (X, Y)	0.03	0.03	0.03*	0.03*	%	typ.
Linearity (Z)	–	0.03	–	0.03*	%	typ.
Repeatability (X, Y)	<2	<2	<2	<2	nm	typ.
Repeatability (Z)	–	<1	–	<1	nm	typ.
Pitch (X,Y)	<±3	<±3	<±5	<±5	µrad	typ.
Yaw (X, Y)	<±10	<±10	<±10	<±10	µrad	typ.
Runout θZ (motion in Z)		<±5		<±5	µrad	typ.
Mechanical properties						
Stiffness	1.5	1.4 (9 in Z)	20	4 (10 in Z)	N/µm	±20 %
Unloaded resonant frequency	500	460 (1400 in Z)	2230	1200 (1100 in Z)	Hz	±20 %
Resonant frequency @ 120 g	370	340 (1060 in Z)	-	-	Hz	±20 %
Resonant frequency @ 200 g	340	295 (650 in Z)	1550	530 (635 in Z)	Hz	±20 %
Push/pull force capacity in motion direction	50/20	50/20	50/20	50/20	N	Max.
Drive properties						
Ceramic type	PICMA® P-885	PICMA® P-885	PICMA® P-885	PICMA® P-885		
Electrical capacitance	6	6 (2.4 in Z)	6.2	6.2 (3.3 in Z)	µF	±20 %
Dynamic operating current coefficient	7.5	7.5 (30 in Z)	25	25 (41 in Z)	µA	(Hz • µm) ±20 %
Miscellaneous						
Operating temperature range	-20 to 80	-20 to 80	-20 to 80	-20 to 80	°C	
Material	Aluminum	Aluminum	Aluminum	Aluminum		
Mass	0.58	0.675	0.58	0.675	kg	±5 %
Cable length	1.5	1.5	1.5	1.5	m	±10 mm
Sensor/ voltage connection	Sub-D special (CD-version) LEMO (CL-version)	Sub-D special (CD-version) LEMO (CL-version)	Sub-D special	Sub-D special		

*With digital controller. Non-linearity of direct drive stages measured with analog controllers is up to 0.1 % typ.

Recommended controller:
Single-channel (1 per axis): E-610 servo controller / amplifier (p. 2-110), E -625 servo controller, bench-top (p. 2-114), E-621 controller module (p. 2-160)
Multi-channel: modular piezo controller system E-500 (p. 2-142) with amplifier module E-503 (three channels) (p. 2-146) or E-505 (1 per axis, high-power) (p. 2-147) and E-509 controller (p. 2-152)
Multi-channel digital controllers: E-710 bench-top (p. 2-128), E-712 modular (p. 2-140), E-725 high-power (p. 2-126), E-761 PCI board (p. 2-130)

P-915K XY-Theta-Z Piezo Stage

3 Degrees of Freedom in the XY Plane

The P-915KPPS is equipped with FEA-modeled flexures for higher stiffness in all three directions of motion

- **Travel Ranges 250 x 250 µm, 16 mrad**
- **Frictionless, High-Precision Flexure Guiding System**
- **High Stiffness >1 N/µm**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**

Model	Travel	Resolution	Load capacity	Settling (system combination with E-621	Dimensions
P-915KPPS XY-Rot-Z-Piezo Stage	250 x 250 µm ±8 mrad	3 nm 15 µrad	2 kg	45 ms (250 µm) 28 ms (16 mrad)	60 x 60 x 100 mm

P-313 PicoCube™ XY(Z) Piezo Scanner

Picometer Precision, High Bandwidth, No Servo Lag, for Scanning Probe Microscopy

A new drive concept allows high-linearity positioning in open-loop operation

- **Ultra-High-Performance Scanner for AFM/SPM**
- **20 Picometers Resolution, <1 nm Hysteresis**
- **Very High Bandwidth with no Servo Lag Due to New Drive Concept**
- **Compact Manipulation Tool for Bio-/Nanotechnology**
- **Resonant Frequency 4.0 kHz (X, Y), 11 kHz (Z)**
- **1 x 1 x 0.8 µm Travel Range**

Model	Travel range (±250 V)	Resolution	Dimensions
P-313.30 PicoCube™ XYZ Scanner	1 x 1 µm (X,Y) 0.8 µm (Z)	0.02 nm (X, Y) 0.14 nm (Z)	30 x 30 x 29.4 mm Moved platform 20 x 20 mm

P-628K Long-Travel XY Piezo Stage with Nanometer Flatness

Novel Active Z-Axis Design Provides Real Time Runout Compensation

The P-628KHFS with an active Z-axis provides an improved straightness of travel with only 9.5 mm added height compared to an P-628.2 nanopositioning stage

- **Closed-Loop Travel Range 800 x 800 µm (up to 1500 µm Possible)**
- **Improved Straightness of Travel <1nm**
- **High-Precision, Cost-Efficient**
- **Resolution to 0.1 nm, 0.02 % Positioning Accuracy**
- **Frictionless, High-Precision Flexure Guiding System**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**

Model	Travel ranges	Unload resonant frequency	Load capacity	Dimensions
P-628KHFS High Flatness XY Stage	800 x 800 µm (X, Y)	75 Hz (X), 105 Hz (Y)	10 N	80 x 80 x (9.5 + 30) mm

Program Overview

- Piezo Ceramic Actuators & Motors
- Piezo Nanopositioning Systems and Scanners
- Active Optics / Tip-Tilt Platforms
- Capacitive Nanometrology Sensors
- Piezo Electronics: Amplifiers and Controllers
- Hexapod 6-Axis Positioners / Robots
- Micropositioning Stages & Actuators
- Photonics Alignment Systems, Solutions for Telecommunications
- Motor Controllers
- Ultrasonic Linear Motors

Request or download the complete PI Nanopositioning & Piezo Actuator Catalog

USA (East) & CANADA

PI (Physik Instrumente) L.P.
16 Albert St.
Auburn, MA 01501
Tel: +1 (508) 832 3456
Fax: +1 (508) 832 0506
info@pi-usa.us
www.pi-usa.us

USA (West) & MEXICO

PI (Physik Instrumente) L.P.
5420 Trabuco Rd., Suite 100
Irvine, CA 92620
Tel: +1 (949) 679 9191
Fax: +1 (949) 679 9292
info@pi-usa.us
www.pi-usa.us

JAPAN

PI Japan Co., Ltd.
Akebono-cho 2-38-5
Tachikawa-shi
J-Tokyo 190
Tel: +81 (42) 526 7300
Fax: +81 (42) 526 7301
info@pi-japan.jp
www.pi-japan.jp

PI Japan Co., Ltd.
Hanahara Dai-ni Building, #703
4-11-27 Nishinakajima,
Yodogawa-ku, Osaka-shi
J-Osaka 532
Tel: +81 (6) 6304 5605
Fax: +81 (6) 6304 5606
info@pi-japan.jp
www.pi-japan.jp

CHINA

Physik Instrumente (PI Shanghai) Co., Ltd.
Building No. 7-301
Longdong Avenue 3000
201203 Shanghai, China
Tel: +86 (21) 687 900 08
Fax: +86 (21) 687 900 98
info@pi-china.cn
www.pi-china.cn

UK & IRELAND

PI (Physik Instrumente) Ltd.
Trent House
University Way,
Cranfield Technology Park,
Cranfield,
Bedford MK43 0AN
Tel: +44 (1234) 756 360
Fax: +44 (1234) 756 369
uk@pi.ws
www.physikinstrumente.co.uk

FRANCE

PI France S.A.S
244 bis, avenue Max Dormoy
92120 Montrouge
Tel: +33 (1) 55 22 60 00
Fax: +33 (1) 41 48 56 62
info.france@pi.ws
www.pi-france.fr

ITALY

Physik Instrumente (PI) S.r.l.
Via G. Marconi, 28
I-20091 Bresso (MI)
Tel: +39 (02) 665 011 01
Fax: +39 (02) 873 859 16
info@pionline.it
www.pionline.it

GERMANY

Physik Instrumente (PI) GmbH & Co. KG
Auf der Römerstr. 1
D-76228 Karlsruhe/Palmbach
Tel: +49 (721) 4846-0
Fax: +49 (721) 4846-100
info@pi.ws · www.pi.ws